

Supporting Information

Synthesis of Perovskite CsPbBr₃ Quantum Dot Superlattice in Borosilicate Glass

Enhao Cao^{a,b}, Jianbei Qiu^{a,b,*}, Dacheng Zhou^{a,b}, Yong Yang^{a,b,*}, Qi Wang^{a,b}, Yugeng Wen^{a,b}

^a School of Materials Science and Engineering, Kunming University of Science and Technology, Kunming 650093, China

^b Key Laboratory of Advanced Materials of Yunnan Province, Kunming 650093, China

* Authors to whom correspondence should be addressed: qiu@kust.edu.cn and yang@kust.edu.cn

Experimental Section

Materials and chemicals

Silicon dioxide (SiO₂, 99.99%), boron oxide (B₂O₃, 98%), zinc oxide (ZnO, 99%), caesium carbonate (Cs₂CO₃, 99%), lead bromide (PbBr₂, 99%) and sodium bromide (NaBr, 99%) were purchased from Aladdin. All chemicals were used without further purification.

Preparation of CsPbBr₃ QDs glass

The samples of pristine glass (PG) were prepared via classical melt-quenching method with nominal composition of (35.7-3.5x)SiO₂-(24.5+3.5x)B₂O₃-9.8ZnO-6Cs₂CO₃-12PbBr₂-12NaBr (mol.%) ($x = 1, 2, 3$, denoted PG1, PG2, PG3, respectively). The raw materials were well mixed and melted at 1150°C for 20 min under ambient atmosphere. Then the melt of mixture was poured onto a preheated brass plate and pressed by another plate. The glasses of PG1, PG2 and PG3 were annealed at 360°C for 2 h, and were then heated at 475°C for 2 h to obtain CsPbBr₃ QDs and/or CsPbBr₃ QD superlattices embedded glasses (denoted QG1, QG2, QG3, respectively).

Characterizations

The CsPbBr₃ QDs and/or CsPbBr₃ QD superlattices embedded glasses were optical polished or ground into powders for subsequent characterization and usage. X-ray diffraction (XRD) analysis was carried out to identify the crystallized phase structure using a Bruker D8 powder diffractometer with a Cu K α incident radiation source. Microstructural observation of samples was conducted on a JEOL JEM-2100 transmission electron microscope (TEM). Absorption spectra were recorded using a Hitachi U4100 spectrophotometer. Photoluminescence (PL) and photoluminescence excitation (PLE), excitation-emission mapping, and PL decay were recorded using an Edinburgh FLS980 spectrophotometer. Raman spectra were determined by a LabRAM HR Evolution Raman spectrometer operated with a 532 nm excitation source.

As shown in Fig. S1, we obtain a primrose transparent CsPbBr₃ QD embedded glass at 475°C while other glasses are either colorless at 435°C or devitrificated at 515°C, 555°C and 595°C.



Fig. S1 The photograph of PG1 glass heated under different temperatures (435°C, 475°C, 515°C, 555°C and 595°C) for 2 h.

Table S1 The quantitative change of topological organization from Raman spectra

glass	[BO ₃]/[BO ₄]	[BO ₃]/[SiO ₄]	[BO ₄]/[SiO ₄]
PG1	1.22	0.81	0.66
PG2	1.25	0.85	0.68
PG3	1.64	1.13	0.68

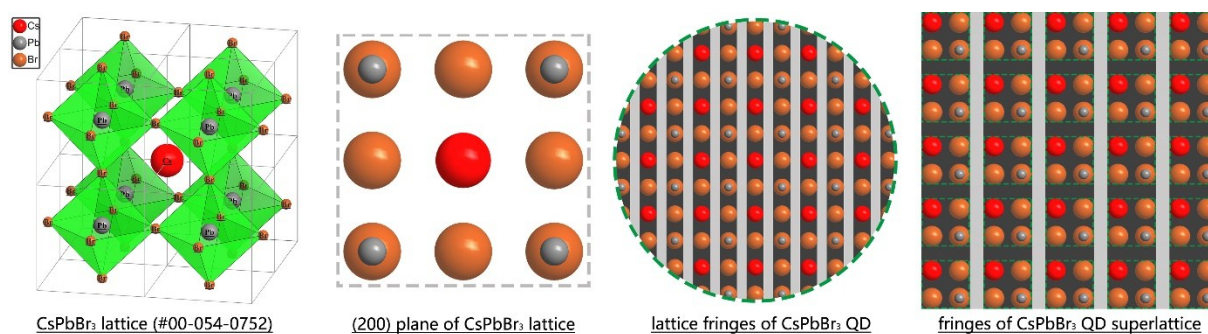


Fig. S2 Schematic illustration. (a) CsPbBr₃ lattice. (b) (200) plane of CsPbBr₃ lattice. (c) lattice fringes of CsPbBr₃ QD. (d) fringes of CsPbBr₃ QD superlattice.

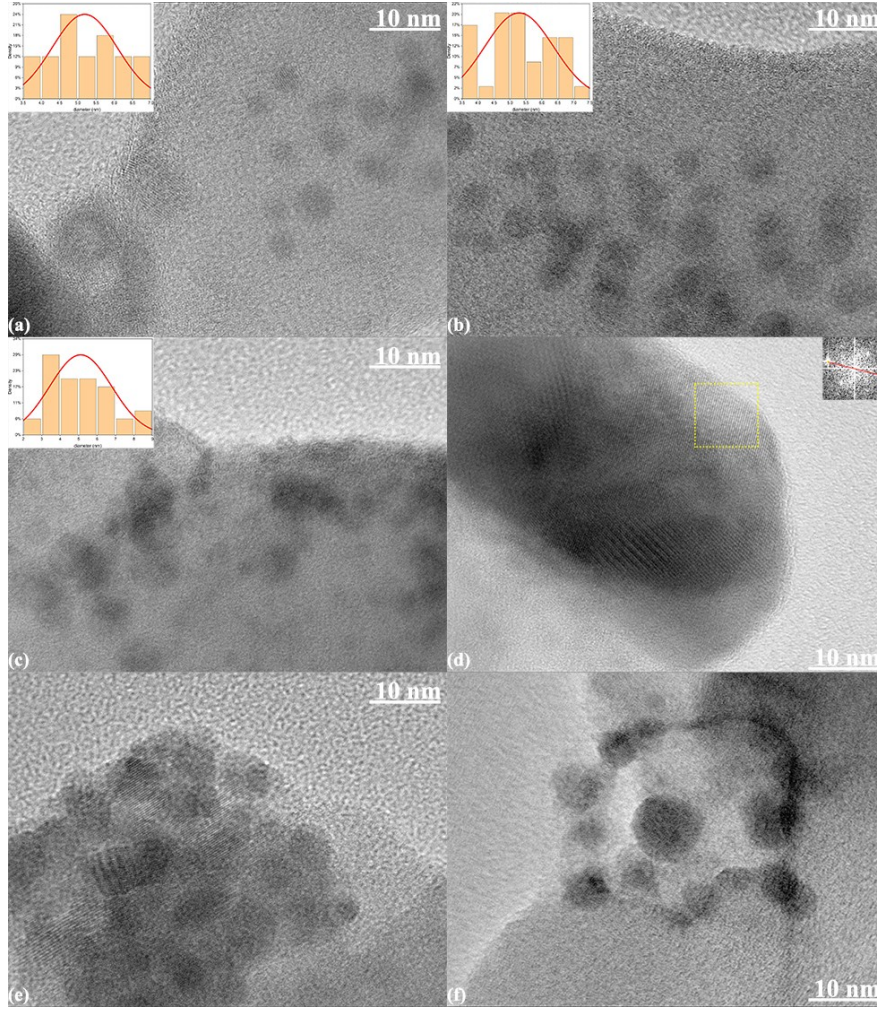


Fig. S3 TEM images of CsPbBr₃ morphology. (a)-(c) distribution of CsPbBr₃ QDs in QG1, QG2, QG3. (d) CsPbBr₃ QD superlattice lattice. (e)-(f) aggregation of CsPbBr₃ QDs.

Table S2 The average size of CsPbBr₃ QD

glass	QG1	QG2	QG3
average size (nm)	5.2	5.3	5.1

We measured their corresponding radiation lifetimes under different power density excitation as shown in Fig. S4. And the average decay lifetime are calculated based on the following equation S(1)

$$\tau_{ave} = \int I(t)dt/I_0 \quad S(1)$$

where I_0 is the peak intensity and $I(t)$ is the recording-time related PL intensity.

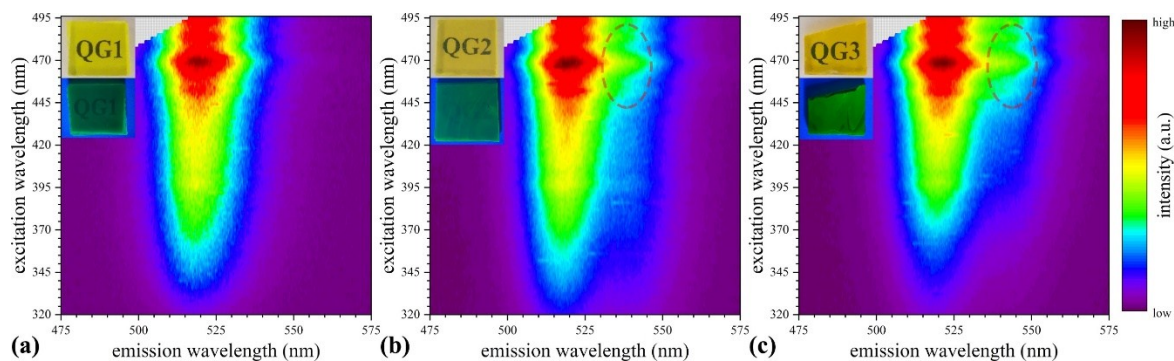


Fig. S4 Two-dimensional excitation-emission mappings of (a) QG1, (b) QG2, (c) QG3, and the inset shows the photograph of CsPbBr₃ QDs embedded glasses under daylight and 365 nm UV lamp.

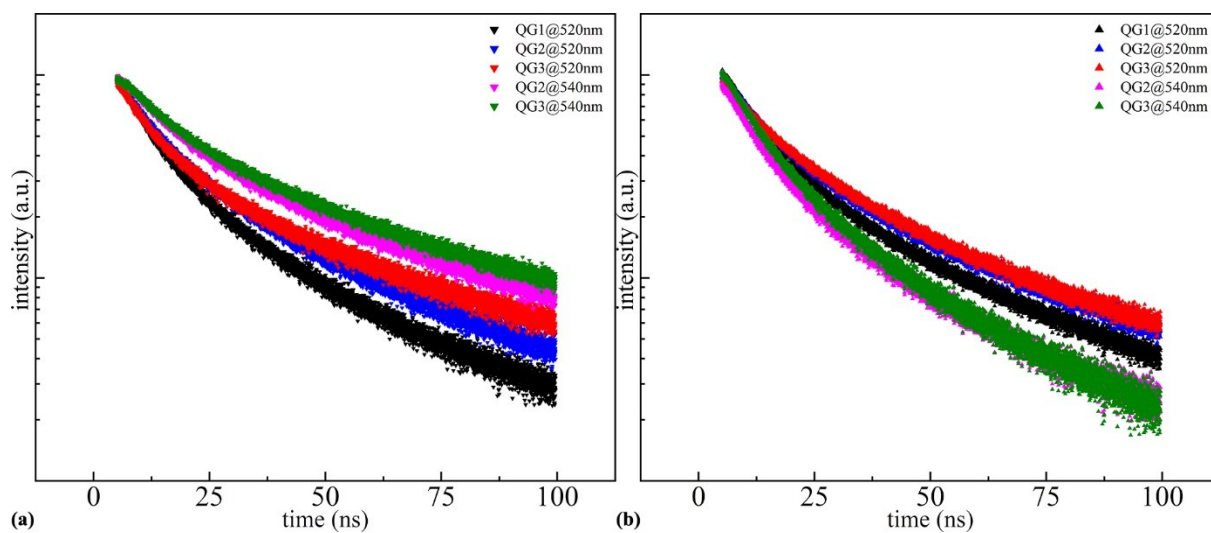


Fig. S5 Time-resolved PL decays curves under (a) low power density excitation and (b) high power density excitation.

Table S3 The lifetimes under different power density excitation

PL decays curves	QG1	QG2	QG3	QG2	QG3
	@520nm	@520nm	@520nm	@540nm	@540nm
τ_{ave} (ns) under low power density excitation	15.87	18.93	19.78	25.74	27.84
τ_{ave} (ns) under high power density excitation	19.29	21.57	21.99	14.65	16.37